

Title : Liaison Statement to SC21/WG7 on ODP and OSE profiling

Source : ISO/IEC JTC1/SGFS

The SGFS thanks SC21/WG7 for their contribution (SC21 N8035 = SGFS N989) and acknowledges the importance of relating concepts and terminology of ODP and OSE profiling. This is identified in the SGFS Issues List.

Unfortunately time did not permit any detailed discussion during the SGFS July 1993 meeting in Seoul, but it will be a topic for discussion at the SGFS Authorized Subgroup Meeting in November 29th - December 3rd, 1993 (tentative location Amsterdam).

SGFS would welcome further input from SC21/WG7 and invites the group to review the latest draft of TR10000-3 (SGFS N1024).

Attached: 3rd WDTR10000-3 (SGFS N1024)